

**DEPARTMENT OF COMMERCE****International Trade Administration****Application(s) for Duty-Free Entry of Scientific Instruments**

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be postmarked on or before February 16, 2010. Address written comments to Statutory Import Programs Staff, Room 3720, U.S. Department of Commerce, Washington, DC 20230. Applications may be examined between 8:30 a.m. and 5 p.m. at the U.S. Department of Commerce in Room 3720.

*Docket Number:* 09-068. *Applicant:* University of Arkansas, 321 Administration Building, Fayetteville, Arkansas 72701.

*Instrument:* Fluorescence Lifetime Imaging Microscope.

*Manufacturer:* PicoQuant Photonics, Germany. *Intended Use:* The instrument will be used to measure both fluorescence lifetime and fluorescence intensity of single nanoparticles and biomolecules. The instrument must be able to perform using lasers with both continuous wave (CW) and pulsed mode. The use of picoseconds pulsed lasers is necessary to measure fluorescence lifetime. The use of CW lasers, so that the fluorophores will be continuously excited, is necessary to measure fluorescence intensity. The driver that controls the laser head provides user-selectable pulsed repetition rates. This instrument is unique in that it is capable of pulsed interleaved excitation (PIE)—Fluorescence Resonance Energy Transfer (FRET) and of allowing repetition rates to be continuously varied down to the 200 kHz range. Furthermore, the instrument is compatible with atomic force microscopy by using objective scanning mode rather than sample scanning mode so that the sample-scanning Atomic Force Microscope (AFM) can be added to the microscope in a future upgrade.

*Justification for Duty-Free Entry:* No instruments of same general category are manufactured in the United States.

*Application accepted by Commissioner of Customs:* December 28, 2009.

Dated January 19, 2010.

**Christopher Cassel,**

*Director, IA Subsidies Enforcement Office.*

[FR Doc. 2010-1337 Filed 1-22-10; 8:45 am]

**BILLING CODE 3510-DS-P**

**DEPARTMENT OF COMMERCE****International Trade Administration****Application(s) for Duty-Free Entry of Scientific Instruments**

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be postmarked on or before February 16, 2010. Address written comments to Statutory Import Programs Staff, Room 3720, U.S. Department of Commerce, Washington, DC 20230. Applications may be examined between 8:30 a.m. and 5 p.m. at the U.S. Department of Commerce in Room 3720.

*Docket Number:* 09-069. *Applicant:* University of Pittsburgh, 4200 Fifth Ave., Pittsburgh, PA 15260. *Instrument:* Electron Microscope. *Manufacturer:* JEOL, Ltd., Japan. *Intended Use:* This instrument will be used to conduct research, focusing on analyzing ultrastructurally the plasticity of the brain and auditory pathway, in particular, different models of hearing loss. This instrument provides the required resolution for such analysis. *Justification for Duty-Free Entry:* No instruments of same general category are manufactured in the United States. *Application accepted by Commissioner of Customs:* December 28, 2009.

*Docket Number:* 09-070. *Applicant:* Haverford College, 370 Lancaster Ave., Haverford, PA 19041. *Instrument:* JEM-1400 Electron Microscope. *Manufacturer:* JEOL Ltd., Japan. *Intended Use:* The instrument will be used for the ultrastructural study of prokaryotic and eukaryotic cell structure, the assembly of peptides and proteins into filaments and other geometries, the analysis of porphyrin and other chemical polymers, and other applications in cell biology, materials science and nanotechnology.

*Justification for Duty-Free Entry:* There are no domestic manufacturers of this type of electron microscope.

*Application accepted by Commissioner of Customs:* December 30, 2009.

Dated: January 19, 2010.

**Christopher Cassel,**

*Director, IA Subsidies Enforcement Office.*

[FR Doc. 2010-1339 Filed 1-22-10; 8:45 am]

**BILLING CODE 3510-DS-P**

**DEPARTMENT OF COMMERCE****International Trade Administration****Yale University, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Electron Microscopes**

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Room 3705, U.S. Department of Commerce, 14th and Constitution Avenue, NW., Washington, DC.

*Docket Number:* 09-064. *Applicant:* Yale University, New Haven, CT 06520-8284. *Instrument:* Electron Microscope, Quanta 3D Dual-Beam Focused Ion-Beam Tool. *Manufacturer:* FEI Company, Czech Republic. *Intended Use:* See notice at 74 FR 67851, December 21, 2009.

*Docket Number:* 09-065. *Applicant:* U.S. Department of Homeland Security, Science and Technology Directorate, Frederick, MD 21702. *Instrument:* Scanning Electron Microscope, Quanta 200 FEG. *Manufacturer:* FEI Company, Czech Republic. *Intended Use:* See notice at 74 FR 67851, December 21, 2009.

*Comments:* None received. *Decision:* Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were ordered. *Reasons:* Each foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring an electron microscope. We know of no electron microscope, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of each instrument.

Dated: January 19, 2010.

**Christopher Cassel,**

*Director, Subsidies Enforcement Office, Import Administration.*

[FR Doc. 2010-1338 Filed 1-22-10; 8:45 am]

**BILLING CODE 3510-DS-P**